Search Notes



Application/Control No.	Applicant(s)/Patent under Reexamination
10/655,221	LEE ET AL.
Examiner	Art Unit

Mike Qi

2871

	SEAR	CHED	
Class	Subclass	Date	Examiner
349	129	1/3/2007	ZQQ
349	123	1/3/2007	ZQQ
349	130	1/3/2007	ZQQ
349	106	1/3/2007	ZQQ
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
349	129	1/3/2007	ZQQ		
349	123	1/3/2007	ZQQ		
349	130,106	1/3/2007	ZQQ		
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DATE	EXMR
1/3/2007	ZQQ
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